

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket No. 0756-2218		Serial No. Not Yet Assigned	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Hongyong ZHANG et al			
				Filing Date: October 25, 2000		Group: 2813	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
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Examiner <i>Evan Pert</i>				Date Considered <i>5/21/01</i>			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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